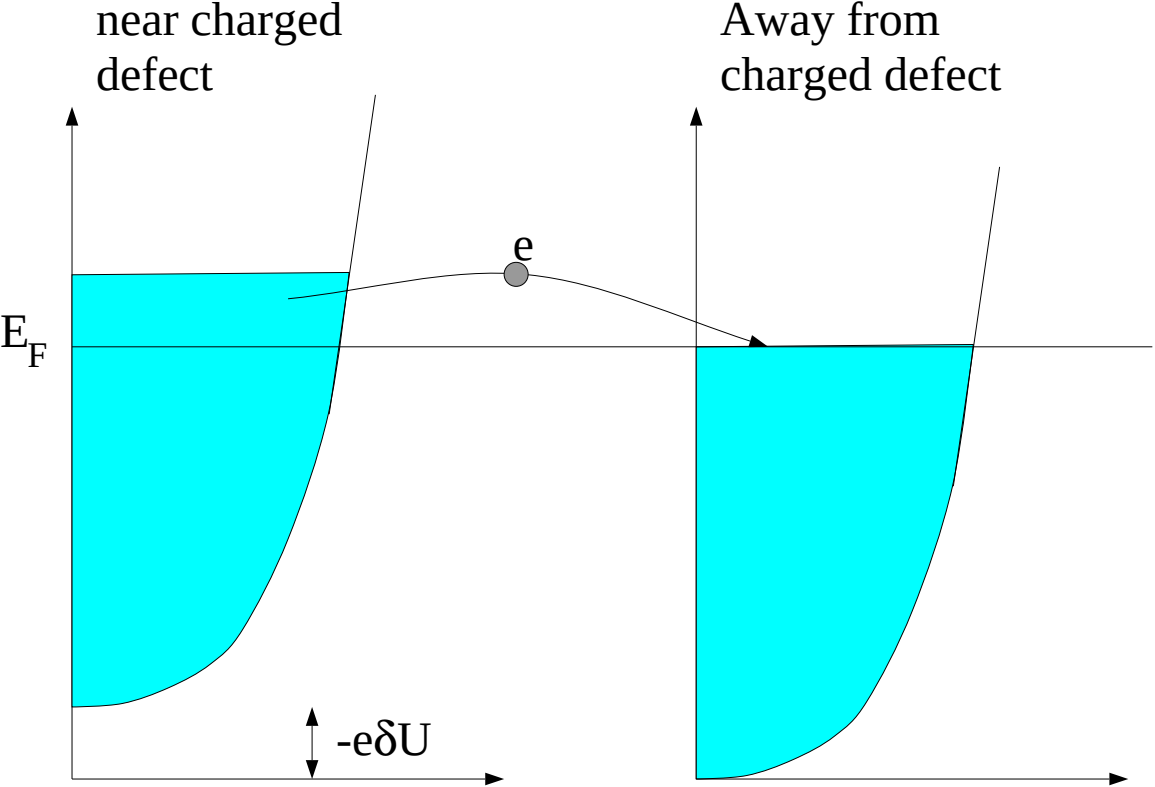
near charged defect
Away from charged defect
e
E_F
$-e\delta U$